

# Mass production and performance of large area Micromegas \ DMM detectors



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**Abstract:** To meet the performance demands of various experiments, the development of high-performance, large-area Micromegas detectors and their mass production have become crucial technical challenges to address. This report will present the advancements in Micromegas manufacturing technology utilizing the thermal bonding method. In recent years, we have successfully produced large-area Micromegas detectors with sensitive areas of  $400 \times 400 \text{ mm}^2$  and  $600 \times 600 \text{ mm}^2$ , and completed the production of a batch of detectors for cosmic ray track detection by implementing quality control methods such as material selection, condition control, and high-voltage aging. Test results demonstrate a position resolution of approximately  $130 \mu\text{m}$  and a detection efficiency exceeding 95%. Furthermore, several large-area, high-performance double layer mesh Micromegas (DMM) detectors have been fabricated successfully. Preliminary test results show gas gain higher than  $10^5$  and the IBF ratio  $< 0.03\%$ , indicating promising application potential in the future.

## Introduction

- The thermal bonding method
- Mass production and optimization
- The Multi-layer tracker system for muography
- The DMM detectors and performance
- Conclusions

## Thermal Bonding Method (TBM)

The thermal bonding method is a highly promising and competitive technology for Micromegas detectors, developed by the MPGD team at the University of Science and Technology of China.



Fig. 1 the thermal bonding method of the Micromegas detector

We have developed a high-stability, high-performance, large-area manufacturing process for Micromegas detectors. This technique offers advantages such as non-etching, environmentally friendly operation, simplicity, and cost-effectiveness. As shown in the illustration on the left, the primary TBM process involves using a rolling machine to bond the stretched stainless-steel mesh onto the PCB to create the avalanche gap of the Micromegas detector. The fundamental performance characteristics of the Micromegas detectors based on the TBM process are detailed in [1][2].

## Mass Production and Improvement

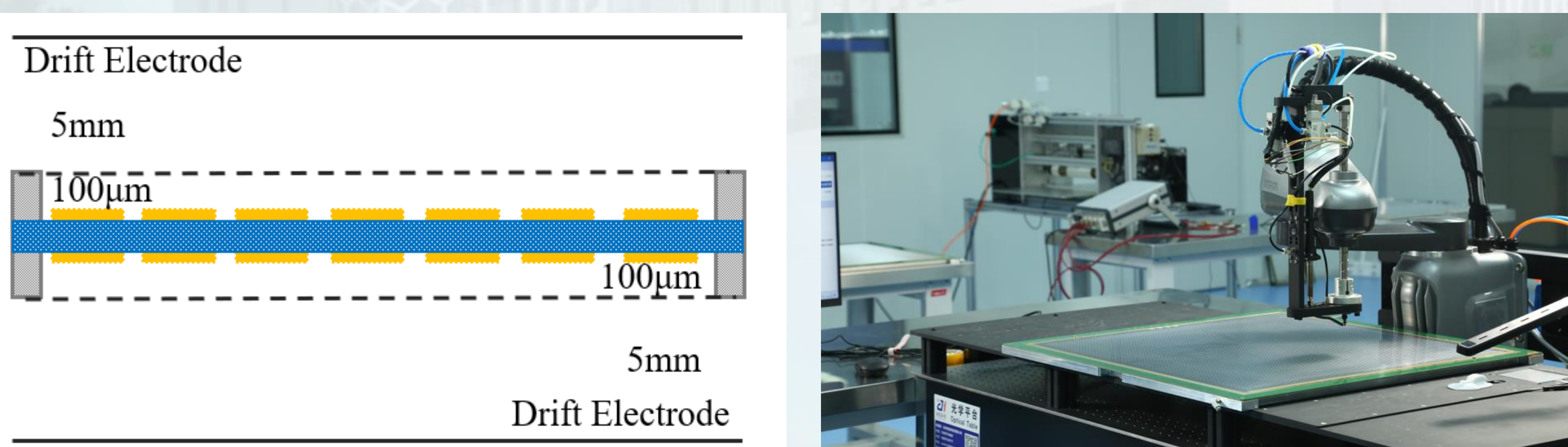


Fig. 2 the "back-to-back" design and the automatic process improvement

In order to improve the stability of large area Micromegas detectors, we have adopted a "back-to-back" structure, distributing the readout strips in the X and Y directions on the upper and lower surfaces of the readout PCB, and constructing identical avalanche and drift regions on both surfaces. This "back-to-back" structure allows independent avalanche amplification in the X and Y directions on the each side of the detector, increasing the signal-noise ratio, thereby lowering voltage requirements and improving detector stability.

In terms of batch production processes, an automated robotic arm replaces manual process to place the spacers, as shows in Fig. 2, improving production efficiency while enhancing process stability, laying a solid foundation for the batch production of high-performance, large area Micromegas detectors.

## Conclusion

- A "back-to-back" structure designed, automated robotic arm and laser cutter are introduce to improve the batch production process.
- Several different sizes standard muography platforms are built.
- Successfully fabricating a large-area double-mesh Micromegas detector with low IBF ratio of  $\sim 0.05\%$ .

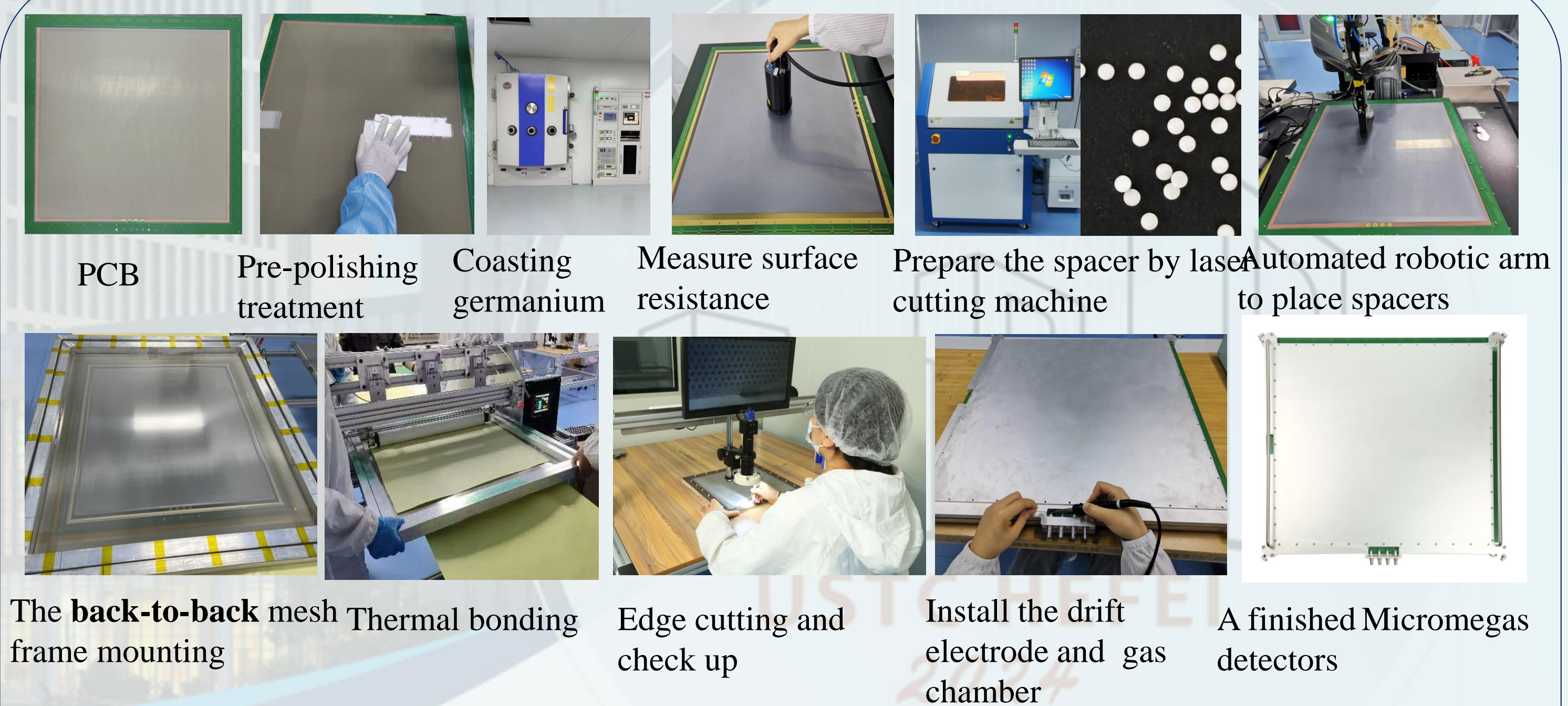


Fig. 3 The full-process of fabricating a Micromegas detector using TBM.

## The Multi-layer Tracker System for Muography

Several muography systems of different sizes and layers have been established in the laboratory and used to calibrate the detector's performance of efficiency and position resolution<sup>[3]</sup>, as shown in Fig. 4. The muon tomography and radiography were established that based on the desktop platform and all-terrain car platform respectively. At the same time, trajectory reconstruction algorithms and multi-layer alignment algorithms are being studied.



Fig. 4 the three different size multi-layer Micromegas detector system for muon tomography or radiography:  $150 \times 150 \text{ mm}^2$ ,  $400 \times 400 \text{ mm}^2$ ,  $600 \times 600 \text{ mm}^2$ .

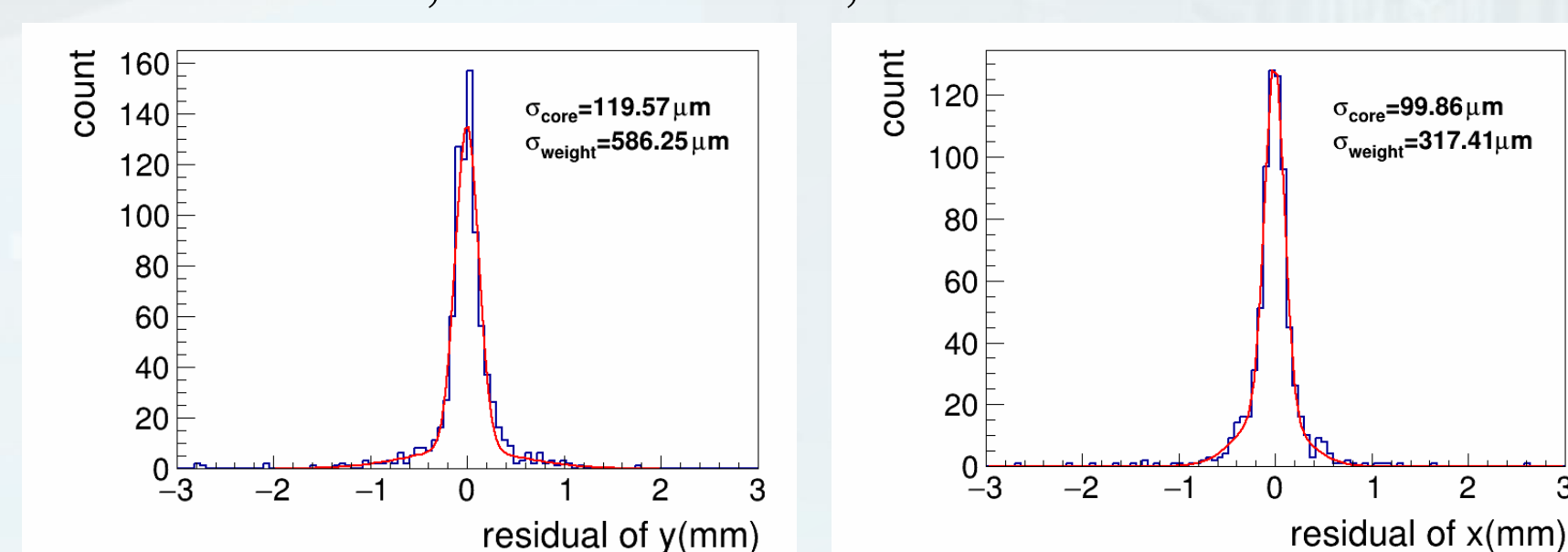


Fig. 5 Spatial resolution of x/y dimensions of  $400 \times 400 \text{ mm}^2$  muon radiography system calibrated by cosmic ray muons.

## DMM detector and performance

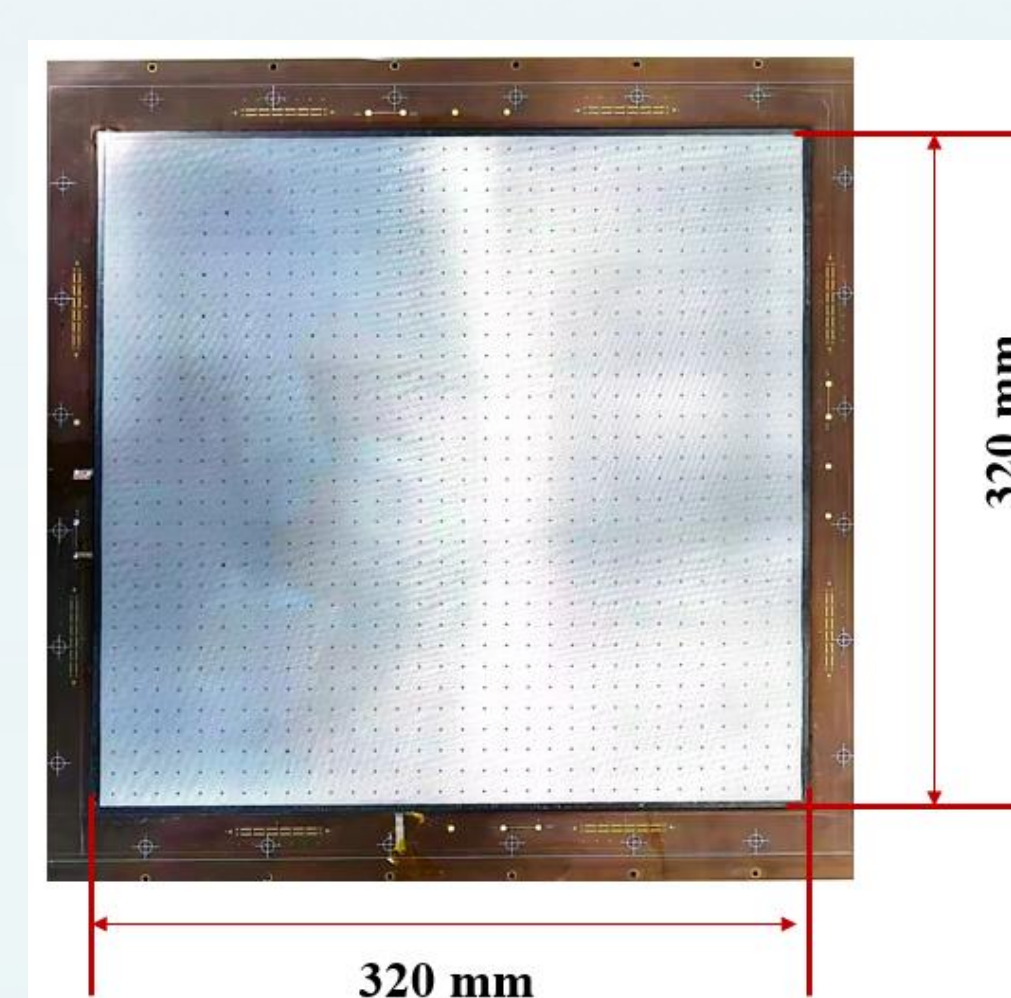


Fig. 6 A  $320 \times 320 \text{ mm}^2$  double-mesh Micromegas detector.

A  $320 \times 320 \text{ mm}^2$  double micro-mesh Micromegas detector was fabricated for RICH detector of the STCF project. This new detector aims to provide better time resolution, lower ion backflow, and higher gain.

- Time resolution  $< 300 \text{ ps}$  for single photon<sup>[4]</sup>
- The gas gain  $> 10^5$
- IBF ratio  $> 0.03\%$ <sup>[5]</sup>

## Reference

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